

Description

The SIM6800M/MV series are high voltage 3-phase motor drivers in which transistors, a pre-drive circuit, and bootstrap circuits (diodes and resistors) are highly integrated.

These products can run on a 3-shunt current detection system and optimally control the inverter systems of lowto medium-capacity motors that require universal input standards.

Features

- Built-in Bootstrap Diodes with Current Limiting Resistors (60 Ω)
- CMOS-compatible Input (3.3 V or 5 V)
- Pb-free (RoHS Compliant)
- Isolation Voltage: 1500 V (for 1 min) UL-recognized Component (File No.: E118037) (SIM6880M UL Recognition Pending)
- Fault Signal Output at Protection Activation (FO Pin)
- High-side Shutdown Signal Input (SD Pin)
- Protections Include: Overcurrent Limit (OCL): Auto-restart Overcurrent Protection (OCP): Auto-restart Undervoltage Lockout for Power Supply High-side (UVLO_VB): Auto-restart Low-side (UVLO_VCC): Auto-restart Thermal Shutdown (TSD): Auto-restart

Typical Application (SIM6811M, SIM6812M)



Package

DIP40

Mold Dimensions: $36.0 \text{ mm} \times 14.8 \text{ mm} \times 4.0 \text{ mm}$



Selection Guide

V _{DSS} /V _{CES}		Part Number	Feature
500 V	2.0 A	SIM6811M	Power MOSFET
300 V	2.5 A	SIM6812M	FOWER MOSFET
600 V	3.0 A	SIM6880M	IGBT with FRD, low switching dissipation
600 V	5.0 A	SIM6822MV	IGBT with FRD, low switching dissipation

Applications

For motor drives such as:

- Refrigerator Compressor Motor
- Fan Motor and Pump Motor for Washer and Dryer
- Fan Motor for Air Conditioner, Air Purifier, and Electric Fan

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1. Absolute Maximum Ratings

Current polarities are defined as follows: current going into the IC (sinking) is positive current (+); current coming out of the IC (sourcing) is negative current (-).

Unless specifically noted, $T_A =$					
Parameter	Symbol	Conditions	Rating	Unit	Remarks
Main Supply Voltage (DC) ⁽¹⁾	V _{DC}	VBB–LSx	450	V	SIM6822MV SIM6880M
Main Power Voltage (Surge) ⁽¹⁾	V _{DC(SURGE)}	VBB–LSx	500	V	SIM6822MV SIM6880M
IGBT / Power MOSFET	V _{DSS}	$V_{CC} = 15 V,$ $I_D = 1 \mu A, V_{IN} = 0 V$	500	N/	SIM6811M SIM6812M
Breakdown Voltage	V _{CES}	$V_{CC} = 15 \text{ V},$ $I_C = 1 \text{ mA}, \text{ V}_{IN} = 0 \text{ V}$	600	V	SIM6822MV SIM6880M
	V _{CC}	VCCx-COM	20	•	
Logic Supply Voltage	V _{BS}	VB1B–U, VB2–V, VB3–W1	20	v	0
			2		SIM6811M
Output Current ⁽²⁾	Io	$T_{C} = 25 \ ^{\circ}C,$	2.5	A	SIM6812M
Output Current	10	$T_J\!<150~^\circ C$	3	А	SIM6880M
			5		SIM6822MV
		$T_{\rm C} = 25 ^{\circ}{\rm C},$	3		SIM6811M
	т	$V_{CC} = 15 V,$	3.75		SIM6812M
Output Current (Pulse)	IOP	pulse width ≤ 1 ms,	4.5	А	SIM6880M
		single pulse	7.5		SIM6822MV
Input Voltage	V _{IN}	HINX–COM, LINX–COM	- 0.5 to 7	V	
FO Pin Voltage	V_{FO}	FO-COM	-0.5 to 7	V	
OCP Pin Voltage	V _{OCP}	OCP-COM	-0.5 to 7	V	
SD Pin Voltage	V _{SD}	SD-COM	-0.5 to 7	V	
LSx Pin Voltage (DC)	V _{LS(DC)}	LSx-COM	-0.5 to 7	V	
LSx Pin Voltage (Surge)	V _{LS(SURGE)}	LSx-COM	-4 to 7	V	
Operating Case Temperature ⁽³⁾	T _{C(OP)}		-30 to 100	°C	
Junction Temperature ⁽⁴⁾	Τ _J		150	°C	
Storage Temperature	T _{STG}		-40 to 150	°C	
Isolation Voltage ⁽⁵⁾	V _{ISO(RMS)}	Between surface of the case and each pin; AC, 60 Hz, 1 min	1500	V	

Unless specifically noted, $T_A = 25$ °C, COM1 = COM2 = COM

⁽¹⁾ Defined for the IGBT-embedded device only.

⁽²⁾ Should be derated depending on an actual case temperature. See Section 15.4.

⁽³⁾ Refers to a case temperature measured during IC operation.

⁽⁴⁾ Refers to the junction temperature of each chip built in the IC, including the control MIC, transistors, and freewheeling diodes.

⁽⁵⁾ Refers to voltage conditions to be applied between all of the pins and the case. All the pins have to be shorted.

2. Recommended Operating Conditions

Unless specifically noted, CO Parameter	Symbol	Conditions	Min.	Тур.	Max.	Unit	Remarks
Main Supply Voltage	V _{DC}	VBB-COM		300	400	V	
	V _{CC}	VCCx–COM	13.5	15.0	16.5	V	
Logic Supply Voltage	V_{BS}	VB1B–U, VB2–V, VB3–W1	13.5		16.5	V	
Input Voltage (HINx, LINx, OCP, SD, FO)	V_{IN}		0		5.5	V	
Minimum Input Pulse Width	t _{IN(MIN)ON}		0.5		_	μs	Ġ
winning input i uise widdi	t _{IN(MIN)OFF}		0.5		_	μs	
Dead Time of Input Signal	t _{DEAD}		1.5		_	μs	0
FO Pin Pull-up Resistor	R _{FO}		3.3	—	10	kΩ	
FO Pin Pull-up Voltage	V_{FO}		3.0	—	5.5	v	
FO Pin Noise Filter Capacitor	C _{FO}		0.001		0.01	μF	
Bootstrap Capacitor	CBOOT		1		220	μF	
		$I_{OP} \leq 3 A$	390				SIM6811M
Shunt Resistor*	Rs	$I_{OP}{\leq}3.75~A$	270			mΩ	SIM6812M
Shuht Resistor*	KS	$I_{OP}{\leq}4.5~A$	270	×		1115.2	SIM6880M
		$I_{OP} \leq 7.5 \text{ A}$	150		_		SIM6822MV
RC Filter Resistor	Ro				100	Ω	
PC Filter Capacitor	Ca	100	1000		2200	рĘ	SIM6822MV SIM6880M
RC Filter Capacitor	Co	0	1000		10000	pF	SIM6811M SIM6812M
PWM Carrier Frequency	fc				20	kHz	
Operating Case Temperature	T _{C(OP)}		_		100	°C	

Unless specifically noted, COM1 = COM2 = COM

* Should be a low-inductance resistor.

3. Electrical Characteristics

Current polarities are defined as follows: current going into the IC (sinking) is positive current (+); current coming out of the IC (sourcing) is negative current (–).

Unless specifically noted, $T_A = 25$ °C, $V_{CC} = 15$ V, COM1 = COM2 = COM.

3.1 Characteristics of Control Parts

Parameter	Symbol	Conditions	Min.	Тур.	Max.	Unit	Remarks
Power Supply Operation							
Logic Operation Start	V _{CC(ON)}	VCCx–COM	10.5	11.5	12.5	V	
Voltage	V _{BS(ON)}	VB1B–U, VB2–V, VB3–W1	9.5	10.5	11.5	V	
Logic Operation Stop	V _{CC(OFF)}	VCCx–COM	10.0	11.0	12.0	V	
Voltage	V _{BS(OFF)}	VB1B–U, VB2–V, VB3–W1	9.0	10.0	11.0	$\mathcal{S}_{\mathbf{V}}$	
	I _{CC}	VCC1 = VCC2, VCC pin current in 3-phase operation		3.2	4.5	mA	
Logic Supply Current	I _{BS}	VB1B–U or VB2–V or VB3–W1; HINx = 5 V; VBx pin current in 1-phase operation	Ā	140	400	μΑ	
Input Signal							
High Level Input Threshold Voltage (HINx, LINx, SD, FO)	V _{IH}	çÓ	_	2.0	2.5	v	
Low Level Input Threshold Voltage (HINx, LINx, SD, FO)	V _{IL}		1.0	1.5	—	v	
High Level Input Current (HINx, LINx)	I _{IH}	$V_{IN} = 5 V$	_	230	500	μΑ	
Low Level Input Current (HINx, LINx)	I_{IL}	$V_{\rm IN}{=}0~V$		—	2	μΑ	
Fault Signal Output							
FO Pin Voltage at Fault Signal Output	V _{FOL}	$V_{FO} = 5 \text{ V}, \text{R}_{FO} = 10 \text{ k}\Omega$	0		0.5	V	
FO Pin Voltage in Normal Operation	V _{FOH}	$V_{FO} = 5 \ V, \ R_{FO} = 10 \ k\Omega$	4.8	_	_	v	
Protection)						
OCL Pin Output Voltage (L)	V _{OCL(L)}		0		0.5	V	
OCL Pin Output Voltage (H)	V _{OCL(H)}		4.5	_	5.5	v	
Current Limit Reference Voltage	V_{LIM}		0.6175	0.6500	0.6825	v	
OCP Threshold Voltage	V _{TRIP}		0.9	1.0	1.1	V	
OCP Hold Time	tP		20	25		μs	
OCP Blanking Time	t _{BK(OCP)}			2		μs	
Current Limit Blanking Time	t _{BK(OCL)}			2		μs	
TSD Operating Temperature	T_{DH}		135	150	165	°C	
TSD Releasing Temperature	T _{DL}		105	120	135	°C	

Parameter	Symbol	Conditions	Min.	Тур.	Max.	Unit	Remarks
Bootstrap Diode Leakage Current	I_{LBD}	$V_R = 500 V$			10	μΑ	
Bootstrap Diode Forward Voltage	V_{FB}	$I_{FB}{=}0.15~A$		1.0	1.3	v	
Bootstrap Diode Series Resistor	R _{BOOT}		45	60	75	Ω	

3.2 Bootstrap Diode Characteristics

3.3 Thermal Resistance Characteristics

Parameter	Symbol	Conditions	Min.	Тур.	Max.	Unit	Remarks
	R _{J-C}	All power MOSFETs operating			3.6	°C/W	SIM6811M SIM6812M
Junction-to-Case Thermal Resistance ⁽¹⁾	$R_{(J-C)Q}^{(2)}$	All IGBTs operating			3.6	°C/W	SIM6822MV SIM6880M
	$R_{(J-C)F}^{(3)}$	All freewheeling diodes operating		-	4.2	°C/W	SIM6822MV SIM6880M
	R_{J-A}	All power MOSFETs operating		A.	25	°C/W	SIM6811M SIM6812M
Junction-to-Ambient Thermal Resistance	R _{(J-A)Q}	All IGBTs operating	_		25	°C/W	SIM6822MV SIM6880M
	R _{(J-A)F}	All freewheeling diodes operating			29	°C/W	SIM6822MV SIM6880M



Figure 3-1. Case Temperature Measurement Point

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⁽¹⁾ Refers to a case temperature at the measurement point described in Figure 3-1, below.

⁽²⁾ Refers to steady-state thermal resistance between the junction of the built-in transistors and the case. For transient thermal characteristics, see Section 15.1.

⁽³⁾ Refers to steady-state thermal resistance between the junction of the built-in freewheeling diodes and the case.

3.4 Transistor Characteristics

Figure 3-2 provides the definitions of switching characteristics described in this and the following sections.



Figure 3-2. Switching Characteristics Definitions

3.4.1 SIM6811M

D	a 1 1		2.0	Ŧ	14	TT .
Parameter	Symbol	Conditions	Min.	Тур.	Max.	Unit
Drain-to-Source Leakage Current	I _{DSS}	$V_{DS} = 500 \text{ V}, V_{IN} = 0 \text{ V}$		_	100	μA
Drain-to-Source On-resistance	R _{DS(ON)}	$I_D = 1.0 \text{ A}, V_{IN} = 5 \text{ V}$	—	3.2	4.0	Ω
Source-to-Drain Diode Forward Voltage	V_{SD}	$I_{SD} = 1.0 \text{ A}, V_{IN} = 0 \text{ V}$		1.0	1.5	V
High-side Switching						
Source-to-Drain Diode Reverse Recovery Time	trr			150		ns
Turn-on Delay Time	t _{d(on)}	$V_{DC} = 300 \text{ V}, I_D = 2.0 \text{ A},$ inductive load,		770	_	ns
Rise Time	tr	$V_{IN} = 0 \rightarrow 5 \text{ V or } 5 \rightarrow 0 \text{ V},$		70		ns
Turn-off Delay Time	t _{d(off)}	$T_J = 25 \ ^\circ C$		690		ns
Fall Time	t _f			30		ns
Low-side Switching						
Source-to-Drain Diode Reverse Recovery Time	t _{rr}			150		ns
Turn-on Delay Time	t _{d(on)}	$V_{DC} = 300 \text{ V}, I_D = 2.0 \text{ A},$ inductive load,		690		ns
Rise Time	t _r	$V_{IN} = 0 \rightarrow 5 \text{ V or } 5 \rightarrow 0 \text{ V},$		90		ns
Turn-off Delay Time	t _{d(off)}	$T_J = 25 \ ^\circ C$		650		ns
Fall Time	t _f			50		ns

3.4.2 **SIM6812M**

Parameter	Symbol	Conditions	Min.	Тур.	Max.	Unit
Drain-to-Source Leakage Current	I _{CES}	$V_{DS} = 500 V, V_{IN} = 0 V$			100	μA
Drain-to-Source On-resistance	V _{CE(SAT)}	$I_D = 1.25 \text{ A}, V_{IN} = 5 \text{ V}$		2.0	2.4	Ω
Source-to-Drain Diode Forward Voltage	V _F	$I_{SD} = 1.25 \text{ A}, V_{IN} = 0 \text{ V}$		1.0	1.5	V
High-side Switching						
Source-to-Drain Diode Reverse Recovery Time	t _{rr}			140	_	ns
Turn-on Delay Time	t _{d(on)}	$V_{DC} = 300 \text{ V}, \text{ I}_{D} = 2.5 \text{ A},$	—	910	— Ġ	ns
Rise Time	tr	inductive load, $V_{IN} = 0 \rightarrow 5 \text{ V or } 5 \rightarrow 0 \text{ V},$ $T_J = 25 \text{ °C}$		100		ns
Turn-off Delay Time	$t_{d(off)}$		—	700		ns
Fall Time	t _f			40		ns
Low-side Switching			A			
Source-to-Drain Diode Reverse Recovery Time	t _{rr}			155	_	ns
Turn-on Delay Time	t _{d(on)}	$V_{DC} = 300 \text{ V}, \text{ I}_D = 2.5 \text{ A},$ inductive load,		875		ns
Rise Time	tr	$V_{IN} = 0 \rightarrow 5 \text{ V or } 5 \rightarrow 0 \text{ V},$		110		ns
Turn-off Delay Time	$t_{d(off)}$	$T_J = 25 \ ^{\circ}C$	· _	775		ns
Fall Time	t _f	<u>so</u>		35		ns
3.4.3 SIM6880M		red	· · · · · ·			
Parameter	Symbol	Conditions	Min.	Typ.	Max.	Unit

3.4.3 SIM6880M

Parameter	Symbol	Conditions	Min.	Тур.	Max.	Unit
Collector-to-Emitter Leakage Current	I _{CES}	$V_{CE} = 600 \text{ V}, V_{IN} = 0 \text{ V}$			1	mA
Collector-to-Emitter Saturation Voltage	V _{CE(SAT)}	$I_{\rm C} = 3.0 \text{ A}, V_{\rm IN} = 5 \text{ V}$		1.85	2.30	V
Diode Forward Voltage	V _F	$I_F = 3.0 \text{ A}, V_{IN} = 0 \text{ V}$		2.0	2.4	V
High-side Switching	, 					
Diode Reverse Recovery Time	t _{rr}			100		ns
Turn-on Delay Time	t _{d(on)}	$V_{DC} = 300 \text{ V}, I_C = 3.0 \text{ A},$	_	880		ns
Rise Time	t _r	inductive load, $V_{IN} = 0 \rightarrow 5 \text{ V or } 5 \rightarrow 0 \text{ V},$	_	120		ns
Turn-off Delay Time	$t_{d(off)}$	$T_{\rm J} = 25 \ ^{\circ}{\rm C}$		740		ns
Fall Time	$t_{\rm f}$			210		ns
Low-side Switching						
Diode Reverse Recovery Time	t _{rr}			100		ns
Turn-on Delay Time	t _{d(on)}	$V_{DC} = 300 \text{ V}, I_C = 3.0 \text{ A},$		820		ns
Rise Time	tr	inductive load, $V_{IN} = 0 \rightarrow 5 \text{ V or } 5 \rightarrow 0 \text{ V},$		140		ns
Turn-off Delay Time	t _{d(off)}	$T_{\rm J} = 25 \ ^{\circ}{\rm C}$		660		ns
Fall Time	$t_{\rm f}$			200		ns

3.4.4 SIM6822MV

Collector-to-Emitter Leakage I_{CES} $V_{CE} = 600 \text{ V}, V_{IN} = 0 \text{ V}$ - - 1 mA Collector-to-Emitter Saturation V_{CESATD} $I_c = 5 \text{ A}, V_{IN} = 5 \text{ V}$ - 1.75 2.2 V Diode Forward Voltage V_F $I_F = 5 \text{ A}, V_{IN} = 0 \text{ V}$ - 2.0 2.4 V High-side Switching Diode Reverse Recovery Time t_{rr} $I_{rr} = 5 \text{ A}, V_{IN} = 0 \text{ V}$ - 80 - ns Turn-on Delay Time t_{rr} $V_{DC} = 300 \text{ V}, I_C = 5 \text{ A},$ - 740 - ns Fall Time t_e $V_{DC} = 300 \text{ V}, I_C = 5 \text{ A},$ - 70 ns Fall Time t_e $T_{TT} = 25 ^{\circ}\text{C}$ - 80 - ns Diode Reverse Recovery Time t_{rr} $V_{DC} = 300 \text{ V}, I_C = 5 \text{ A},$ - 690 - ns Turn-on Delay Time t_e $V_{DC} = 300 \text{ V}, I_C = 5 \text{ A},$ - 540 - ns Fall Time t_e $V_{DC} = 50 \text{ V}$	Parameter	Symbol	Conditions	Min.	Тур.	Max.	Unit
$\begin{array}{ c c c c c c c c c c c c c c c c c c c$		I _{CES}	$V_{CE} = 600 \text{ V}, V_{IN} = 0 \text{ V}$	—		1	mA
High-side SwitchingDiode Reverse Recovery Time t_{rr} Turn-on Delay Time $t_{d(on)}$ Rise Time t_{t} Turn-off Delay Time $t_{d(off)}$ Fall Time t_{f} Diode Reverse Recovery Time t_{rr} Turn-off Delay Time $t_{d(off)}$ Fall Time t_{f} Diode Reverse Recovery Time t_{rr} Turn-on Delay Time $t_{d(on)}$ Rise Time t_{rr} Turn-on Delay Time $t_{d(on)}$ Rise Time t_{r} Turn-off Delay Time $t_{d(off)}$ Fall Time t_{rr}		V _{CE(SAT)}	$I_C = 5 A, V_{IN} = 5 V$	—	1.75	2.2	V
Diode Reverse Recovery Time t_{rr} $V_{DC} = 300 \text{ V}, \text{ Ic} = 5 \text{ A}, \text{inductive load, } V_{IN} = 0 \rightarrow 5 \text{ V or } 5 \rightarrow 0 \text{ V}, T_{I} = 25 ^{\circ}\text{C}$ $ 80$ $ ns$ Rise Time t_r $T_{urn-off}$ Delay Time $t_{d(off)}$ $V_{DC} = 300 \text{ V}, \text{ Ic} = 5 \text{ A}, \text{inductive load, } V_{IN} = 0 \rightarrow 5 \text{ V or } 5 \rightarrow 0 \text{ V}, T_{I} = 25 ^{\circ}\text{C}$ $ 70$ ns Fall Time t_f $V_{DC} = 300 \text{ V}, \text{ Ic} = 5 \text{ A}, \text{inductive load, } V_{DC} = 300 \text{ V}, \text{ Ic} = 5 \text{ A}, \text{inductive load, } V_{DC} = 300 \text{ V}, \text{ Ic} = 5 \text{ A}, \text{inductive load, } V_{DC} = 300 \text{ V}, \text{ Ic} = 5 \text{ A}, \text{inductive load, } V_{DC} = 300 \text{ V}, \text{ Ic} = 5 \text{ A}, \text{inductive load, } V_{DC} = 0 \rightarrow 5 \text{ V or } 5 \rightarrow 0 \text{ V}, T_{I} = 25 ^{\circ}\text{C}$ $ 80$ $ ns$ Turn-on Delay Time $t_{d(off)}$ $V_{DC} = 300 \text{ V}, \text{ Ic} = 5 \text{ A}, \text{inductive load, } V_{DC} = 0 \rightarrow 5 \text{ V or } 5 \rightarrow 0 \text{ V}, T_{I} = 25 ^{\circ}\text{C}$ $ 540$ $ ns$ Fall Time t_f t_f $V_{DC} = 300 \text{ V}, \text{ Ic} = 5 \text{ A}, \text{inductive load, } V_{DC} = 0 \rightarrow 5 \text{ V or } 5 \rightarrow 0 \text{ V}, T_{I} = 25 ^{\circ}\text{C}$ $ 540$ $ ns$ Fall Time t_f t_f $ 100$ $ ns$	Diode Forward Voltage	$V_{\rm F}$	$I_F = 5 A, V_{IN} = 0 V$	—	2.0	2.4	V
Turn-on Delay Time $t_{d(on)}$ $V_{DC} = 300 \text{ V}, I_C = 5 \text{ A}, inductive load, V_{IN} = 0 \rightarrow 5 \text{ V or } 5 \rightarrow 0 \text{ V}, T_J = 25 ^{\circ}\text{C} — 740 — ns Turn-off Delay Time t_{d(on)} V_{IN} = 0 \rightarrow 5 \text{ V or } 5 \rightarrow 0 \text{ V}, T_J = 25 ^{\circ}\text{C} — 70 ns Fall Time t_f — 70 — ns Low-side Switching — 100 — ns Diode Reverse Recovery Time t_{rr} V_{DC} = 300 \text{ V}, I_C = 5 \text{ A}, inductive load, V_{IN} = 0 \rightarrow 5 \text{ V} \text{ or } 5 \rightarrow 0 \text{ V}, — 80 — ns Rise Time t_r V_{DC} = 300 \text{ V}, I_C = 5 \text{ A}, inductive load, V_{IN} = 0 \rightarrow 5 \text{ V} \text{ or } 5 \rightarrow 0 \text{ V}, — 100 — ns Turn-off Delay Time t_{d(on)} V_{IN} = 0 \rightarrow 5 \text{ V} \text{ or } 5 \rightarrow 0 \text{ V}, — 540 — ns Fall Time t_r V_{IN} = 0 \rightarrow 5 \text{ V} \text{ or } 5 \rightarrow 0 \text{ V}, — — 100 — ns Fall Time t_r V_{IN} = 0 \rightarrow 5 \text{ V} \text{ or } 5 \rightarrow 0 \text{ V}, — — 100 — ns $	High-side Switching						
Rise Time t_r inductive load, $V_{IN} = 0 \rightarrow 5$ V or $5 \rightarrow 0$ V, $T_J = 25 °C$ -70nsTurn-off Delay Time $t_{d(off)}$ $T_J = 25 °C$ -570nsFall Timetr T_r -100-nsLow-side SwitchingDiode Reverse Recovery Time t_{rr} $V_{DC} = 300$ V, $I_C = 5$ A, inductive load, $V_{IN} = 0 \rightarrow 5$ V or $5 \rightarrow 0$ V, $T_J = 25 °C$ -80-nsTurn-off Delay Time $t_{d(off)}$ $T_J = 25 °C$ -540-nsFall Time t_r $V_{DC} = 300$ V, $I_C = 5 A$, $I_J = 25 °C$ -540-nsTurn-off Delay Time $t_{d(off)}$ $T_J = 25 °C$ -540-nsFall Time t_r $V_{DC} = 300 V_{T} = 0 + 5 V_{T$	Diode Reverse Recovery Time	t _{rr}		—	80		ns
Rise Time t_r Turn-off Delay Time $t_{d(off)}$ t $V_{IN} = 0 \rightarrow 5 \text{ V or } 5 \rightarrow 0 \text{ V},$ $T_J = 25 °C$ $ 100$ $ ns$ Fall Time t_f $V_{IN} = 0 \rightarrow 5 \text{ V or } 5 \rightarrow 0 \text{ V},$ $T_J = 25 °C$ $ 570$ ns Low-side SwitchingDiode Reverse Recovery Time t_{rr} t (number of the dom) $V_{DC} = 300 \text{ V}, I_C = 5 \text{ A},$ inductive load, $V_{IN} = 0 \rightarrow 5 \text{ V or } 5 \rightarrow 0 \text{ V},$ $T_J = 25 °C$ $ 80$ $ ns$ Turn-off Delay Time $t_{d(off)}$ T Fall Time t_r $V_{IN} = 0 \rightarrow 5 \text{ V or } 5 \rightarrow 0 \text{ V},$ $T_J = 25 °C$ $ 540$ $ ns$ Fall Time t_r t_r $ 100$ $ ns$	Turn-on Delay Time	t _{d(on)}			740	— Ċ	ns
$\begin{array}{c c c c c c c c c c c c c c c c c c c $	Rise Time	t _r		—	70	A	ns
Low-side SwitchingDiode Reverse Recovery Time t_{rr} Turn-on Delay Time $t_{d(on)}$ Rise Time t_r Turn-off Delay Time $t_{d(off)}$ Fall Time t_f	Turn-off Delay Time	$t_{d(off)}$		—	570		ns
Diode Reverse Recovery Time t_{rr} $N_{DC} = 300 \text{ V}, I_C = 5 \text{ A},$ $ 80$ $ ns$ Turn-on Delay Time $t_d(on)$ $V_{DC} = 300 \text{ V}, I_C = 5 \text{ A},$ 690 $ ns$ Rise Time t_r $V_{IN} = 0 \rightarrow 5 \text{ V}$ or $5 \rightarrow 0 \text{ V},$ 100 $ ns$ Turn-off Delay Time $t_d(off)$ $T_J = 25 \text{ °C}$ $ 540$ $ ns$ Fall Time t_f t_f $ 100$ $ ns$	Fall Time	t _f			100	- 1	ns
Turn-on Delay Time $t_{d(on)}$ $V_{DC} = 300 \text{ V}, I_C = 5 \text{ A},$ 690 $ ns$ Rise Time t_r r $inductive load,$ $V_{IN} = 0 \rightarrow 5 \text{ V} \text{ or } 5 \rightarrow 0 \text{ V},$ 100 $ ns$ Turn-off Delay Time $t_{d(off)}$ $T_J = 25 \text{ °C}$ $ 540$ $ ns$ Fall Time t_f $ 100$ $ ns$	Low-side Switching						
Rise Time t_r inductive load, $V_{IN} = 0 \rightarrow 5$ V or $5 \rightarrow 0$ V, $T_J = 25$ °C100 $-$ nsFall Time t_f $ 100$ $ ns$	Diode Reverse Recovery Time	t _{rr}		-~	80		ns
Rise Time t_r $V_{IN} = 0 \rightarrow 5$ V or $5 \rightarrow 0$ V, $=$ 100 $=$ nsTurn-off Delay Time $t_{d(off)}$ $T_J = 25$ °C $ 540$ $-$ nsFall Time t_f $ 100$ $-$ ns	Turn-on Delay Time	t _{d(on)}			690		ns
Turn-off Delay Time $t_{d(off)}$ $T_J = 25 \ ^{\circ}C$ $-$ 540 $-$ nsFall Time t_f $ 100$ $ ns$	Rise Time	t _r			100		ns
Fall Time tr - 100 - ns	Turn-off Delay Time	$t_{d(off)}$		\succ –	540		ns
AdtRecommended	Fall Time	t _f			100		ns
	Reco	mm	ende				

4. Mechanical Characteristics

Parameter	Conditions	Min.	Тур.	Max.	Unit	Remarks
Heatsink Mounting Screw Torque	*	0.294		0.441	N·m	
Flatness of Heatsink Attachment Area	See Figure 4-1.	0		100	μm	
Package Weight			5.2		g	

* Requires using a metric screw of M2.5 and a plain washer of 6.0 mm (ϕ). For more on screw tightening, see Section 13.2.



Figure 4-1. Flatness Measurement Position

5. Insulation Distance

Parameter	Conditions	Min.	Тур.	Max.	Unit	Remarks
Clearance	Between heatsink* and	1.5		2.1	mm	
Creepage	leads. See Figure 5-1.	1.7	_		mm	

* Refers to when a heatsink to be mounted is flat. If your application requires a clearance exceeding the maximum distance given above, use an alternative (e.g., a convex heatsink) that will meet the target requirement.



Figure 5-1. Insulation Distance Definitions

6. Truth Table

Table 6-1 is a truth table that provides the logic level definitions of operation modes.

In the case where HINx and LINx pin signals in each phase are high at the same time, both the high- and low-side transistors become on (simultaneous on-state). Therefore, HINx and LINx signals, the input signals for the HINx and LINx pins, require dead time setting so that such a simultaneous on-state event can be avoided.

After the IC recovers from a UVLO_VCC condition, the low-side transistors resume switching in accordance with the input logic levels of the LINx signals (level-triggered), whereas the high-side transistors resume switching at the next rising edge of an HINx signal (edge-triggered).

After the IC recovers from a UVLO_VB condition, the high-side transistors resume switching at the next rising edge of an HINx signal (edge-triggered).

			1	
Mode	HINx	LINx	High-side Transistor	Low-side Transistor
	L	L	OFF	OFF
New 10	Н	L	ON	OFF
Normal Operation	L	Н	OFF	ON
	Н	Н	ON	ON
	L	L	OFF	OFF
External Shutdown Signal Input	Н	L	ON	OFF
FO = Low Level	L	Н	OFF	OFF
	Н	Н	ON	OFF
	L	L	OFF	OFF
Undervoltage Lockout for	Н	L	OFF	OFF
High-side Power Supply (UVLO_VB)	L	Н	OFF	ON
	Н	H	OFF	ON
	L	L	OFF	OFF
Undervoltage Lockout for Low-side Power Supply (UVLO_VCC)	Н	L	OFF	OFF
	L	Н	OFF	OFF
(0,120_,000)	Н	Н	OFF	OFF
	L	L	OFF	OFF
Oregonia Directo etile in (OCD)	Н	L	ON	OFF
Overcurrent Protection (OCP)	L	Н	OFF	OFF
	Н	Н	ON	OFF
	L	L	OFF	OFF
Overcurrent Limit (OCL)	Н	L	OFF	OFF
(OCL = SD)	L	Н	OFF	ON
	Н	Н	OFF	ON
\rightarrow	L	L	OFF	OFF
Thermal Chutdow (TCD)	Н	L	ON	OFF
Thermal Shutdown (TSD)	L	Н	OFF	OFF
	Н	Н	ON	OFF

Table 6-1. Truth Table for Operation Modes

G

7. Block Diagrams



Figure 7-2. SIM6822MV or SIM6880M

8. Pin Configuration Definitions



9. Typical Applications

CR filters and Zener diodes should be added to your application as needed. This is to protect each pin against surge voltages causing malfunctions, and to avoid the IC being used under the conditions exceeding the absolute maximum ratings where critical damage is inevitable. Then, check all the pins thoroughly under actual operating conditions to ensure that your application works flawlessly.



Figure 9-1. SIM6811M / SIM6812M Typical Application Using a Single Shunt Resistor



Figure 9-2. SIM6811M / SIM6812M Typical Application Using Three Shunt Resistors

10. Physical Dimensions

• DIP40 Package



- Dimensions in millimeters
- Pb-free (RoHS compliant)
- The leads illustrated above are for reference only, and may not be actual states of being bent.
- Maximum gate burr height is 0.3 mm.

• Reference Through Hole Size and Layout



11. Marking Diagram

• SIM6800M Series



12. Functional Descriptions

Unless specifically noted, this section uses the following definitions:

- All the characteristic values given in this section are typical values.
- All the circuit diagrams listed in this section represent the type of IC that incorporates power MOSFETs. All the functional descriptions in this section are also applicable to the type of IC that incorporates IGBTs.
- For pin and peripheral component descriptions, this section employs a notation system that denotes a pin name with the arbitrary letter "x", depending on context. Thus, "the VCCx pin" is used when referring to either or both of the VCC1 and VCC2 pins.
- The COM1 pin is always connected to the COM2 pin.

12.1 Turning On and Off the IC

The procedures listed below provide recommended startup and shutdown sequences. To turn on the IC properly, do not apply any voltage on the VBB, HINx, and LINx pins until the VCCx pin voltage has reached a stable state ($V_{CC(ON)} \ge 12.5$ V).

It is required to fully charge bootstrap capacitors, C_{BOOTx} , at startup (see Section 12.2.2).

To turn off the IC, set the HINx and LINx pins to logic low (or "L"), and then decrease the VCCx pin voltage.

12.2 Pin Descriptions

12.2.1 U, V, V1, V2, W1, and W2

The U, V1, V2, W1, and W2 pins are the outputs of the three phases, and serve as the connection terminals to the 3-phase motor. The V pin must be connected to a bootstrap capacitor of the V-phase. Do not connect the 3-phase motor to the V pin. The V1 and W1 pins must be connected to the V2 and W2 pins on a PCB, respectively.

The U, V (V1) and W1 pins are the grounds for the VB1A (VB1B), VB2, and VB3 pins.

The U, V and W1 pins are connected to the negative nodes of bootstrap capacitors, C_{BOOTx} . The V pin is internally connected to the V1 pin.

Since high voltages are applied to these output pins (U, V1, V2, W1, and W2), it is required to take measures for insulating as follows:

- Keep enough distance between the output pins and low-voltage traces.
- Coat the output pins with insulating resin.

12.2.2 VB1A, VB1B, VB2, and VB3

These pins are connected to bootstrap capacitors for the high-side floating supply.

In actual applications, use either of the VB1A or VB1B pin because they are internally connected. Voltages across the VBx and these output pins should be maintained within the recommended range (i.e., the Logic Supply Voltage, V_{BS}) given in Section 2.

A bootstrap capacitor, C_{BOOTx} , should be connected in each of the traces between the VB1A (VB1B) and U pins, the VB2 and V pins, the VB3 and W1 pins.

For proper startup, turn on the low-side transistor first, then fully charge the bootstrap capacitor, C_{BOOTx} .

For the capacitance of the bootstrap capacitors, C_{BOOTx} , choose the values that satisfy Equations (1) and (2). Note that capacitance tolerance and DC bias characteristics must be taken into account when you choose appropriate values for C_{BOOTx} .

$$C_{BOOTx}(\mu F) > 800 \times t_{L(OFF)}$$
(1)

$$1 \ \mu F \le C_{\text{BOOTx}} \le 220 \ \mu F \tag{2}$$

In Equation (1), let $t_{L(OFF)}$ be the maximum off-time of the low-side transistor (i.e., the non-charging time of C_{BOOTx}), measured in seconds.

Even while the high-side transistor is off, voltage across the bootstrap capacitor keeps decreasing due to power dissipation in the IC. When the VBx pin voltage decreases to $V_{BS(OFF)}$ or less, the high-side undervoltage lockout (UVLO_VB) starts operating (see Section 12.3.3.1). Therefore, actual board checking should be done thoroughly to validate that voltage across the VBx pin maintains over 11.0 V ($V_{BS} > V_{BS(OFF)}$) during a low-frequency operation such as a startup period.

As Figure 12-1 shows, a bootstrap diode, D_{BOOTx} , and a current-limiting resistor, R_{BOOTx} , are internally placed in series between the VCC1 and VBx pins.

Time constant for the charging time of C_{BOOTx} , τ , can be computed by Equation (3):

$$\tau = C_{BOOTx} \times R_{BOOTx} \quad , \tag{3}$$

where C_{BOOTx} is the optimized capacitance of the bootstrap capacitor, and R_{BOOTx} is the resistance of the current-limiting resistor (60 $\Omega \pm 25\%$).



Figure 12-1. Bootstrap Circuit

Figure 12-2 shows an internal level-shifting circuit. A high-side output signal, HOx, is generated according to an input signal on the HINx pin. When an input signal on the HINx pin transits from low to high (rising edge), a "Set" signal is generated. When the HINx input signal transits from high to low (falling edge), a "Reset" signal is generated. These two signals are then transmitted to the high-side by the level-shifting circuit and are input to the SR flip-flop circuit. Finally, the SR flip-flop circuit feeds an output signal, Q (i.e., HOx).

Figure 12-3 is a timing diagram describing how noise or other detrimental effects will improperly influence the level-shifting process. When a noise-induced rapid voltage drop between the VBx and output pins (U, V, or W1; hereafter "VBx-HSx") occurs after the Set signal generation, the next Reset signal cannot be sent to the SR flip-flop circuit. And the state of an HOx signal stays logic high (or "H") because the SR flip-flop does not respond. With the HOx state being held high (i.e., the high-side transistor is in an on-state), the next LINx signal turns on the low-side transistor and causes a simultaneously-on condition, which may result in critical damage to the IC. To protect the VBx pin against such a noise effect, add a bootstrap capacitor, CBOOTx, in each phase. CBOOTx must be placed near the IC and be connected between the VBx and HSx pins with a minimal length of traces. To use an electrolytic capacitor, add a 0.01 μ F to 0.1 μ F bypass capacitor, C_{Px}, in parallel near these pins used for the same phase.



Figure 12-2. Internal Level-shifting Circuit



Figure 12-3. Waveforms at VBx-HSx Voltage Drop

12.2.3 VCC1 and VCC2

These are the logic supply pins for the built-in control MIC. The VCC1 and VCC2 pins must be externally connected on a PCB because they are not internally connected. To prevent malfunction induced by supply ripples or other factors, put a 0.01 μ F to 0.1 μ F ceramic capacitor, C_{VCC}, near these pins. To prevent damage caused by surge voltages, put an 18 V to 20 V Zener diode, DZ, between the VCCx and COMx pins.

Voltages to be applied between the VCCx and COMx pins should be regulated within the recommended operational range of V_{CC} , given in Section 2.



Figure 12-4. VCCx Pin Peripheral Circuit

12.2.4 COM1 and COM2

These are the logic ground pins for the built-in control MIC. The COM1 and COM2 pins should be connected externally on a PCB because they are not internally connected. Varying electric potential of the logic ground can be a cause of improper operations. Therefore, connect the logic ground as close and short as possible to shunt resistors, R_{Sx} , at a single-point ground (or star ground) which is separated from the power ground (see Figure

12-5).



Figure 12-5. Connections to Logic Ground

12.2.5 HIN1, HIN2, and HIN3; LIN1, LIN2, and LIN3

These are the input pins of the internal motor drivers for each phase. The HINx pin acts as a high-side controller; the LINx pin acts as a low-side controller.

Figure 12-6 shows an internal circuit diagram of the HINx or LINx pin. This is a CMOS Schmitt trigger circuit with a built-in 20 k Ω pull-down resistor, and its input logic is active high.

Input signals across the HINx–COMx and the LINx– COMx pins in each phase should be set within the ranges provided in Table 12-1, below. <u>Note that dead time</u> <u>setting must be done for HINx and LINx signals because</u> the IC does not have a dead time generator.

The higher PWM carrier frequency rises, the more switching loss increases. Hence, the PWM carrier frequency must be set so that operational case temperatures and junction temperatures have sufficient margins against the absolute maximum ranges, specified in Section 1.

If the signals from the microcontroller become unstable, the IC may result in malfunctions. To avoid this event, the outputs from the microcontroller output line should not be high impedance.

Also, if the traces from the microcontroller to the HINx or LINx pin (or both) are too long, the traces may be interfered by noise. Therefore, it is recommended to add an additional filter or a pull-down resistor near the HINx or LINx pin as needed (see Figure 12-7).

Here are filter circuit constants for reference:

- R_{IN1x} : 33 Ω to 100 Ω
- R_{INx} : 1 k Ω to 10 k Ω
- C_{INx} : 100 pF to 1000 pF

Care should be taken in adding R_{IN1x} and R_{IN2x} to the traces. When they are connected to each other, the input

voltage of the HINx and LINx pins becomes slightly lower than the output voltage of the microcontroller.

Table 12-1.	Input Signals for HINx and LINx Pins

Parameter	High Level Signal	Low Level Signal		
Input Voltage	$3 V < V_{IN} < 5.5 V$	$0 \ V < V_{IN} < 0.5 \ V$		
Input				
Pulse	≥0.5 µs	≥0.5 μs		
Width				
PWM		6		
Carrier	≤20 kHz			
Frequency				
Dead	1	5.00		
Time	≥1.5 μs			
	U1 .	5 V		



Figure 12-6. Internal Circuit Diagram of HINx or LINx Pin



Figure 12-7. Filter Circuit for HINx or LINx Pin

12.2.6 VBB

This is the input pin for the main supply voltage, i.e., the positive DC bus. All of the power MOSFET drains (IGBT collectors) of the high-side are connected to this pin. Voltages between the VBB and COMx pins should be set within the recommended range of the main supply voltage, V_{DC} , given in Section 2.

To suppress surge voltages, put a 0.01 μ F to 0.1 μ F bypass capacitor, C_S, near the VBB pin and an electrolytic capacitor, C_{DC}, with a minimal length of PCB traces to the VBB pin.

12.2.7 LS1, LS2, LS3A, and LS3B

These are the source (emitter) pins of the low-side power MOSFETs (IGBTs). For current detection, the LS1, LS2, and LS3A (LS3B) pins should be externally connected to shunt resistors, R_{Sx} . In actual applications, use either of the LS3A or LS3B pin because they are internally connected.

When connecting a shunt resistor, use a resistor with low inductance, and place it as near as possible to the IC with a minimum length of traces to the LSx and COMx pins. The LSx pin may be prone to negative potential due to high inductance, which is mainly caused by longer circuit traces; as a result, circuit malfunctions tend to occur. To avoid such malfunction, design your application so that PCB traces will have inductance as low as possible. In applications where long PCB traces are required, add a fast recovery diode, D_{RSx} , between the LSx and COMx pins in order to prevent the IC from malfunctioning. Do not design an application where the LSx Pin Voltage (Surge), $V_{LS(SURGE)}$, decreases to -4 V or less.



12.2.8 OCP and OCL

The OCP pin serves as the input for the overcurrent protections which monitor the currents going through the output transistors.

In normal operation, the OCL pin logic level is low. In case one or more of the protections listed below are activated by an OCP input signal, the OCL pin logic level becomes high. If the OCL pin is connected to the SD pin so that the SD pin will respond to the OCL input signal, the high-side transistors can be turned off when the protections (OCP and OCL) are activated.

• Overcurrent Limit (OCL)

When the OCP pin voltage exceeds the Current Limit Reference Voltage, V_{LIM} , the OCL pin logic level becomes high. While the OCL is in working, the output

transistors operate according to an input signal (HINx or LINx). If the OCL pin is connected to the SD pin, the high-side transistors can be turned off. For a more detailed OCL description, see Section 12.3.4.

• Overcurrent Pprotection (OCP)

This function detects inrush currents larger than those detected by the OCL. When the OCP pin voltage exceeds the OCP Threshold Voltage, V_{TRIP} , the IC operates as follows: the OCL pin = logic high, the low-side transistors = off, the FO pin = logic low.

In addition, if the OCL pin is connected to the SD pin, the high-side transistors can be turned off. For a more detailed OCP description, see Section 12.3.5.

12.2.9 SD

When a 5 V or 3.3 V signal is input to the SD pin, the high-side transistors turn off independently of any HINx signals. This is because the SD pin does not respond to a pulse shorter than an internal filter of $3.3 \ \mu s$ (typ.).

The SD-OCL pin connection, as described in Section 12.2.8, allows the IC to turn off the high-side transistors at OCL or OCP activation. Also, inputting the inverted signal of the FO pin to the SD pin permits all the high-and low-side transistors to turn off, when the IC detects an abnormal condition (i.e., some or all of the protections such as TSD, OCP, and UVLO are activated).

12.2.10 FO

This pin operates as the fault signal output and the lowside shutdown signal input. Sections 12.3.1 and 12.3.2 explain the two functions in detail, respectively. Figure 12-9 illustrates an internal circuit diagram of the FO pin and its peripheral circuit.



Figure 12-9. Internal Circuit Diagram of FO Pin and Its Peripheral Circuit

Because of its open-collector nature, the FO pin should be tied by a pull-up resistor, R_{FO} , to the external power supply. The external power supply voltage (i.e., the FO Pin Pull-up Voltage, V_{FO}) should range from 3.0 V to 5.5 V. When the pull-up resistor, R_{FO} , has a too small resistance, the FO pin voltage at fault signal output

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becomes high due to the saturation voltage drop of a builtin transistor, Q_{FO} . Therefore, it is recommended to use a 3.3 k Ω to 10 k Ω pull-up resistor. To suppress noise, add a filter capacitor, C_{FO} , near the IC with minimizing a trace length between the FO and COMx pins.

For avoiding repeated OCP activations, the external microcontroller must shut off any input signals to the IC within an OCP hold time, t_P , after the internal transistor (Q_{FO}) turn-on. t_P is 15 µs where minimum values of thermal characteristics are taken into account. (For more details, see Section 12.3.5.) Our recommendation is to use a 0.001 µF to 0.01 µF filter capacitor.

12.3 Protection Functions

This section describes the various protection circuits provided in the SIM6800M/MV series. The protection circuits include the undervoltage lockout for power supplies (UVLO), the overcurrent protection (OCP), and the thermal shutdown (TSD). In case one or more of these protection circuits are activated, the FO pin outputs a fault signal; as a result, the external microcontroller can stop the operations of the three phases by receiving the fault signal. The external microcontroller can also shut down IC operations by inputting a fault signal to the FO pin.

In the following functional descriptions, "HOx" denotes a gate input signal on the high-side transistor, whereas "LOx" denotes a gate input signal on the low-side transistor.

12.3.1 Fault Signal Output

In case one or more of the following protections are actuated, an internal transistor, Q_{FO} , turns on, then the FO pin becomes logic low (≤ 0.5 V).

- 1) Low-side undervoltage lockout (UVLO_VCC)
- 2) Overcurrent protection (OCP)
- 3) Thermal shutdown (TSD)

While the FO pin is in the low state, all the low-side transistors turn off. In normal operation, the FO pin outputs a high signal of about 5 V. Motor operations must be controlled by the external microcontroller so that it can immediately stop the motor when fault signals are detected. To prevent the IC from having permanent damage at OCP activation, be sure to set the motor operation to stop within $t_P = 25 \ \mu s$ (typ.). t_P is the fault signal output time of the FO pin, fixed by a built-in feature of the IC itself (see Section 12.3.5). To resume the motor operation thereafter, set the motor to be resumed after a lapse of ≥ 2 seconds.

12.3.2 Shutdown Signal Input

The FO pin also acts as the input pin of shutdown signals. When the FO pin becomes logic low, all the low-side transistors turn off.

The voltages and pulse widths of the shutdown signals to be applied between the FO and COMx pins are listed in Table 12-2.

Table 12-2. Shutdown Signals

Parameter	High Level Signal	Low Level Signal
Input Voltage	$3 \ V < V_{IN} < 5.5 \ V$	$0 \ V < V_{IN} < 0.5 \ V$
Input Pulse Width	_	≥6 µs
	Ċ	

12.3.3 Undervoltage Lockout for Power Supply (UVLO)

In case the gate-driving voltages of the output transistors decrease, their steady-state power dissipations increase. This overheating condition may cause permanent damage to the IC in the worst case. To prevent this event, the SIM6800M/MV series has the undervoltage lockout (UVLO) circuits for both of the high- and low-side power supplies.

12.3.3.1. Undervoltage Lockout for High-side Power Supply (UVLO_VB)

Figure 12-10 shows operational waveforms of the undervoltage lockout for high-side power supply (i.e., UVLO_VB).

When the voltage between the VBx and output pins (VBx–HSx shown in Figure 12-10) decreases to the Logic Operation Stop Voltage ($V_{BS(OFF)} = 10.0$ V) or less, the UVLO_VB circuit in the corresponding phase gets activated and sets an HOx signal to logic low. When the voltage between the VBx and HSx pins increases to the Logic Operation Start Voltage ($V_{BS(ON)} = 10.5$ V) or more, the IC releases the UVLO_VB operation. Then, the HOx signal becomes logic high at the rising edge of the first input command after the UVLO_VB release. Any fault signals are not output from the FO pin during the UVLO_VB operation. In addition, the VBx pin has an internal UVLO_VB filter of about 3 μ s, in order to prevent noise-induced malfunctions.



Figure 12-10. UVLO_VB Operational Waveforms

12.3.3.2. Undervoltage Lockout for Low-side Power Supply (UVLO_VCC)

Figure 12-11 shows operational waveforms of the undervoltage lockout for low-side power supply (i.e., UVLO VCC).

When the VCC2 pin voltage decreases to the Logic Operation Stop Voltage ($V_{CC(OFF)} = 11.0$ V) or less, the UVLO_VCC circuit in the corresponding phase gets activated and sets both of HOx and LOx signals to logic low. When the VCC2 pin voltage increases to the Logic Operation Start Voltage ($V_{CC(ON)} = 11.5$ V) or more, the IC releases the UVLO_VCC operation. Then, the IC resumes the following transmissions: an LOx signal according to an LINx pin input command; an HOx signal according to the rising edge of the first HINx pin input command after the UVLO_VCC release. During the UVLO_VCC operation, the FO pin becomes logic low and sends fault signals. In addition, the VCC2 pin has an internal UVLO_VCC filter of about 3 μ s, in order to prevent noise-induced malfunctions.



Figure 12-11. UVLO_VCC Operational Waveforms

12.3.4 Overcurrent Limit (OCL)

The overcurrent limit (OCL) is a protection against relatively low overcurrent conditions. Figure 12-12 shows an internal circuit of the OCP and OCL pins; Figure 12-13 shows OCL operational waveforms.

When the OCP pin voltage increases to the Current Limit Reference Voltage ($V_{LIM} = 0.6500$ V) or more, and remains in this condition for a period of the Current Limit Blanking Time ($t_{BK(OCP)} = 2 \ \mu s$) or longer, the OCL circuit is activated. Then, the OCL pin goes logic high.

During the OCL operation, the gate logic levels of the low-side transistors respond to an input command on the LINx pin. To turn off the high-side transistors during the OCL operation, connect the OCL and SD pins on a PCB. The SD pin has an internal filter of about 3.3 µs (typ.).

When the OCP pin voltage falls below V_{LIM} (0.6500 V), the OCL pin logic level becomes low. After the OCL pin logic has become low, the high-side transistors remain turned off until the first low-to-high transition on an HINx input signal occurs (i.e., edge-triggered).



Figure 12-12. Internal Circuit of OCP and OCL Pins



Figure 12-13. OCL Operational Waveforms (OCL = SD)

12.3.5 Overcurrent Protection (OCP)

The overcurrent protection (OCP) is a protection against large inrush currents (i.e., high di/dt). Figure 12-14 is an internal circuit diagram describing the OCP pin and its peripheral circuit.

The OCP pin detects overcurrents with voltage across external shunt resistors, R_{Sx} . Because the OCP pin is internally pulled down, the OCP pin voltage increases proportionally to a rise in the currents running through the shunt resistors, R_{Sx} .



Figure 12-14. Internal Circuit Diagram of OCP Pin and Its Peripheral Circuit



Figure 12-15 is a timing chart that represents operation waveforms during OCP operation. When the OCP pin voltage increases to the OCP Threshold Voltage ($V_{TRIP} = 1.0 \text{ V}$) or more, and remains in this condition for a period of the OCP Blanking Time ($t_{BK} = 2 \mu s$) or longer, the OCP circuit is activated. The enabled OCP circuit shuts off the low-side transistors and puts the FO pin into a low state. Then, output current decreases as a result of the output transistor turn-offs. Even if the OCP pin voltage falls below V_{TRIP} , the IC holds the FO pin in the low state for a fixed OCP hold time, $t_P = 25 \mu s$ (typ.). Then, the output transistors operate according to input signals.

The OCP is used for detecting abnormal conditions, such as an output transistor shorted. In case short-circuit conditions occur repeatedly, the output transistors can be destroyed. For this reason, motor operations must be controlled by the external microcontroller so that it can immediately stop the motor when fault signals are detected.

For proper shunt resistor setting, your application must meet the following:

- Use the shunt resistor that has a recommended resistance, R_{Sx} (see Section 2).
- Set the OCP pin input voltage to vary within the rated OCP pin voltages, V_{OCP} (see Section 1).
- Keep the current through the output transistors below the rated output current (pulse), I_{OP} (see Section 1).

It is required to use a resistor with low internal inductance because high-frequency switching current will flow through the shunt resistors, R_{Sx} . In addition, choose a resistor with allowable power dissipation according to your application.

When you connect a CR filter (i.e., a pair of a filter resistor, R_0 , and a filter capacitor, C_0) to the OCP pin,

care should be taken in setting the time constants of R_O and C_O . The larger the time constant, the longer the time that the OCP pin voltage rises to V_{TRIP} . And this may cause permanent damage to the transistors. Consequently, a propagation delay of the IC must be taken into account when you determine the time constants. For R_O and C_O , their time constants must be set to the values listed in Table 12-3. And place C_O as close as possible to the IC with minimizing a trace length between the OCP and COMx pins.

Note that overcurrents are undetectable when one or more of the U, V/V1/V2, and W1/W2 pins or their traces are shorted to ground (ground fault). In case any of these pins falls into a state of ground fault, the output transistors may be destroyed.

Table 12-3. Reference Time Constants for CR Filter	Table 12-3.	Reference	Time	Constants	for	CR Filter
--	-------------	-----------	------	-----------	-----	-----------

Part Number	Time Constant (µs)
SIM6811M SIM6812M	≤2
SIM6822MV SIM6880M	≤0.2

12.3.6 Thermal Shutdown (TSD)

The SIM6800M/MV series incorporates the thermal shutdown (TSD) circuit. Figure 12-16 shows TSD operational waveforms. In case of overheating (e.g., increased power dissipation due to overload, or elevated ambient temperature at the device), the IC shuts down the low-side output transistors.

The TSD circuit in the MIC monitors temperatures (see Section 7). When the temperature of the MIC exceeds the TSD Operating Temperature ($T_{DH} = 150$ °C), the TSD circuit is activated.

When the temperature of the MIC decreases to the TSD Releasing Temperature ($T_{DL} = 120$ °C) or less, the shutdown condition is released. The output transistors then resume operating according to input signals.

During the TSD operation, the FO pin becomes logic low and transmits fault signals.

Note that junction temperatures of the output transistors themselves are not monitored; therefore, do not use the TSD function as an overtemperature prevention for the output transistors.



ror

13. Design Notes

13.1 PCB Pattern Layout

Figure 13-1 shows a schematic diagram of a motor drive circuit. The circuit consists of current paths having high frequencies and high voltages, which also bring about negative influences on IC operation, noise interference, and power dissipation. Therefore, PCB trace layouts and component placements play an important role in circuit designing.

Current loops, which have high frequencies and high voltages, should be as small and wide as possible, in order to maintain a low-impedance state. In addition, ground traces should be as wide and short as possible so that radiated EMI levels can be reduced.



Figure 13-1. High-frequency, High-voltage Current Paths

13.2 Considerations in Heatsink Mounting

The following are the key considerations and the guidelines for mounting a heatsink:

- Be sure to use a metric screw of M2.5 and a plain washer of 6.0 mm (φ). When tightening the screws, use a torque screwdriver and tighten them within the range of screw torque defined in Section 4. Be sure to avoid uneven tightening. Temporarily tighten the two screws first, then tighten them equally on both sides until the specified screw torque is reached.
- When mounting a heatsink, it is recommended to use silicone greases. If a thermally conductive sheet or an

electrically insulating sheet is used, package cracks may be occurred due to creases at screw tightening. Therefore, you should conduct thorough evaluations before using these materials.

- When applying a silicone grease, make sure that there are no foreign substances between the IC and a heatsink. Extreme care should be taken not to apply a silicone grease onto any device pins as much as possible. The following requirements must be met for proper grease application:
- Grease thickness: 100 µm
- Heatsink flatness: $\pm 100 \ \mu m$
- Apply silicone grease within the area indicated in Figure 13-2, below.



Figure 13-2. Reference Application Area for Thermal Silicone Grease

13.3 Considerations in IC Characteristics Measurement

When measuring the breakdown voltage or leakage current of the transistors incorporated in the IC, note that the gate and source (emitter) of each transistor should have the same potential. Moreover, care should be taken during the measurement because each transistor is connected as follows:

- All the high-side drains (collectors) are internally connected to the VBB pin.
- In the U-phase, the high-side source (emitter) and the low-side drain (collector) are internally connected, and are also connected to the U pin.

(In the V- and W-phases, the high- and low-side transistors are unconnected inside the IC.)

The gates of the high-side transistors are pulled down to the corresponding output (U, V/V1, and W1) pins; similarly, the gates of the low-side transistors are pulled down to the COM2 pin.

When measuring the breakdown voltage or leakage current of the transistors, note that all of the output (U, V/V1, and W1), LSx, and COMx pins must be appropriately connected. Otherwise, the switching transistors may result in permanent damage.

The following are circuit diagrams representing typical measurement circuits for breakdown voltage: Figure 13-3 shows the high-side transistor (Q_{IH}) in the U-phase;

Figure 13-4 shows the low-side transistor (Q_{1L}) in the Uphase. And all the pins that are not represented in these figures are open.

When measuring the high-side transistors, leave all the non-measuring pins open. When measuring the low-side transistors, connect only the measuring LSx pin to the COMx pin and leave the other pins open.



Figure 13-3. Typical Measurement Circuit for Highside Transistor (Q_{1H}) in U-phase



Figure 13-4. Typical Measurement Circuit for Lowside Transistor (Q_{1L}) in U-phase

14. Calculating Power Losses and Estimating Junction Temperatures

This section describes the procedures to calculate power losses in switching transistors, and to estimate a junction temperature. Note that the descriptions listed here are applicable to the SIM6800M/MV series, which is controlled by a 3-phase sine-wave PWM driving strategy.

For quick and easy references, we offer calculation support tools online. Please visit our website to find out more.

- DT0050: Motor Driver ICs (with MOSFETs) Power Loss Calculation Tool <u>http://www.semicon.sanken-ele.co.jp/en/calc-</u> tool/mosfet caltool en.html
- DT0052: Motor Driver ICs (with IGBTs) Power Loss Calculation Tool <u>http://www.semicon.sanken-ele.co.jp/en/calc-</u> tool/igbtall_caltool_en.html

14.1 IGBT

Total power loss in an IGBT can be obtained by taking the sum of steady-state loss, P_{ON} , and switching loss, P_{SW} . The following subsections contain the mathematical procedures to calculate these losses (P_{ON} and P_{SW}) and the junction temperature of all IGBTs operating.

14.1.1 IGBT Steady-state Loss, Pon

Steady-state loss in an IGBT can be computed by using the V_{CE(SAT)} vs. I_C curves, listed in Section 15.3.1. As expressed by the curves in Figure 14-1, a linear approximation at a range the I_C is actually used is obtained by: V_{CE(SAT)} = $\alpha \times I_C + \beta$. The values gained by the above calculation are then applied as parameters in Equation (4), below. Hence, the equation to obtain the IGBT steady-state loss, P_{ON}, is:

$$P_{\rm ON} = \frac{1}{2\pi} \int_0^{\pi} V_{\rm CE(SAT)} (\phi) \times I_{\rm C}(\phi) \times DT \times d\phi$$
$$= \frac{1}{2} \alpha \left(\frac{1}{2} + \frac{4}{3\pi} M \times \cos \theta \right) I_{\rm M}^2$$
$$+ \frac{\sqrt{2}}{\pi} \beta \left(\frac{1}{2} + \frac{\pi}{8} M \times \cos \theta \right) I_{\rm M}.$$
(4)

Where:

 $V_{CE(SAT)}$ is the collector-to-emitter saturation voltage of the IGBT (V),

 I_C is the collector current of the IGBT (A),

DT is the duty cycle, which is given by

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$$\mathrm{DT} = \frac{1 + \mathrm{M} \times \sin(\varphi + \theta)}{2},$$

M is the modulation index (0 to 1),

 $\cos\theta$ is the motor power factor (0 to 1), I_M is the effective motor current (A),

 α is the slope of the linear approximation in the V_{CE(SAT)} vs. I_C curve, and

 β is the intercept of the linear approximation in the $V_{CE(SAT)}$ vs. I_C curve.



Figure 14-1. Linear Approximate Equation of $V_{CE(SAT)}$ vs. I_C

14.1.2 IGBT Switching Loss, Psw

Switching loss in an IGBT can be calculated by Equation (5), letting I_M be the effective current value of the motor:

$$P_{SW} = \frac{\sqrt{2}}{\pi} \times f_{C} \times \alpha_{E} \times I_{M} \times \frac{V_{DC}}{300} .$$
 (5)

Where:

 $f_{\rm C}$ is the PWM carrier frequency (Hz),

V_{DC} is the main power supply voltage (V), i.e., the VBB pin input voltage, and

 α_E is the slope of the switching loss curve (see Section 15.3.2).

14.1.3 Estimating Junction Temperature of IGBT

The junction temperature of all IGBTs operating, T_J , can be estimated with Equation (6):

$$T_{J} = R_{(J-C)Q} \times \{(P_{ON} + P_{SW}) \times 6\} + T_{C}.$$
 (6)

Where:

- $R_{(J-C)Q}$ is the junction-to-case thermal resistance (°C/W) of all the IGBTs operating, and
- T_C is the case temperature (°C), measured at the point defined in Figure 3-1.

14.2 Power MOSFET

Total power loss in a power MOSFET can be obtained by taking the sum of the following losses: steady-state loss, P_{RON} ; switching loss, P_{SW} ; the steady-state loss of a body diode, P_{SD} . In the calculation procedure we offer, the recovery loss of a body diode, P_{RR} , is considered negligibly small compared with the ratios of other losses.

The following subsections contain the mathematical procedures to calculate these losses (P_{RON} , P_{SW} , and P_{SD}) and the junction temperature of all power MOSFETs operating.

14.2.1 Power MOSFET Steady-state Loss, PRON

Steady-state loss in a power MOSFET can be computed by using the $R_{DS(ON)}$ vs. I_D curves, listed in Section 15.3.1. As expressed by the curves in Figure 14-2, a linear approximation at a range the I_D is actually used is obtained by: $R_{DS(ON)} = \alpha \times I_D + \beta$. The values gained by the above calculation are then applied as parameters in Equation (7), below. Hence, the equation to obtain the power MOSFET steady-state loss, P_{RON} , is:

$$P_{\text{RON}} = \frac{1}{2\pi} \int_0^{\pi} I_D(\phi)^2 \times R_{DS(ON)}(\phi) \times DT \times d\phi$$
$$= 2\sqrt{2}\alpha \left(\frac{1}{3\pi} + \frac{3}{32}M \times \cos\theta\right) I_M^3$$
$$+ 2\beta \left(\frac{1}{8} + \frac{1}{3\pi}M \times \cos\theta\right) I_M^2.$$
(7)

Where:

I_D is the drain current of the power MOSFET (A),

 $R_{DS(ON)}$ is the drain-to-source on-resistance of the power MOSFET (Ω),

DT is the duty cycle, which is given by

$$DT = \frac{1 + M \times \sin(\phi + \theta)}{2}$$

M is the modulation index (0 to 1),

 $\cos\theta$ is the motor power factor (0 to 1),

 I_M is the effective motor current (A),

- α is the slope of the linear approximation in the $R_{DS(ON)}$ vs. I_D curve, and
- β is the intercept of the linear approximation in the $R_{DS(ON)}\,vs.\;I_D$ curve.

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Figure 14-2. Linear Approximate Equation of R_{DS(ON}) vs. I_D

14.2.2 Power MOSFET Switching Loss, Psw

Switching loss in a power MOSFET can be calculated by Equation (8), letting I_M be the effective current value of the motor:

$$P_{SW} = \frac{\sqrt{2}}{\pi} \times f_C \times \alpha_E \times I_M \times \frac{V_{DC}}{300} .$$
 (8)

Where:

f_C is the PWM carrier frequency (Hz),

V_{DC} is the main power supply voltage (V), i.e., the VBB pin input voltage, and

 α_E is the slope of the switching loss curve (see Section 15.3.2).

14.2.3 Body Diode Steady-state Loss, Psp

Steady-state loss in the body diode of a power MOSFET can be computed by using the V_{SD} vs. I_{SD} curves, listed in Section 15.3.1. As expressed by the curves in Figure 14-3, a linear approximation at a range the I_{SD} is actually used is obtained by: $V_{SD} = \alpha \times I_{SD} + \beta$. The values gained by the above calculation are then applied as parameters in Equation (9), below. Hence, the equation to obtain the body diode steady-state loss, P_{SD}, is:

$$P_{SD} = \frac{1}{2\pi} \int_0^{\pi} V_{SD}(\phi) \times I_{SD}(\phi) \times (1 - DT) \times d\phi$$

$$= \frac{1}{2} \alpha \left(\frac{1}{2} - \frac{4}{3\pi} M \times \cos \theta \right) I_{M}^{2} + \frac{\sqrt{2}}{\pi} \beta \left(\frac{1}{2} - \frac{\pi}{8} M \times \cos \theta \right) I_{M}$$
⁽⁹⁾

Where:

V_{SD} is the source-to-drain diode forward voltage of the power MOSFET (V),

I_{SD} is the source-to-drain diode forward current of the power MOSFET (A),

DT is the duty cycle, which is given by

$$DT = \frac{1 + M \times \sin(\phi + \theta)}{2} ,$$

M is the modulation index (0 to 1).

 $\cos\theta$ is the motor power factor (0 to 1),

 I_M is the effective motor current (A),

- α is the slope of the linear approximation in the V_{SD} vs. I_{SD} curve, and
- β is the intercept of the linear approximation in the V_{SD} vs. I_{SD} curve.



Figure 14-3. Linear Approximate Equation of V_{SD} vs. I_{SD}

14.2.4 Estimating Junction Temperature of Power MOSFET

The junction temperature of all power MOSFETs operating, T_J, can be estimated with Equation (10):

$$T_J = R_{J-C} \times \{(P_{ON} + P_{SW} + P_{SD}) \times 6\} + T_C.$$
 (10)

Where:

- R_{J-C} is the junction-to-case thermal resistance (°C/W) of all the power MOSFETs operating, and
- T_C is the case temperature (°C), measured at the point defined in Figure 3-1.

15. Performance Curves

15.1 Transient Thermal Resistance Curves

The following graphs represent transient thermal resistance (the ratios of transient thermal resistance), with steadystate junction-to-case thermal resistance = 1. Note that the graph representing that of the IGBT-embedded device shows only IGBT characteristics; no freewheeling diode characteristics are included.





15.2 Performance Curves of Control Parts

Figure 15-4 to Figure 15-28 provide performance curves of the control parts integrated in the SIM6800M/MV series, including variety-dependent characteristics and thermal characteristics. T_J represents the junction temperature of the control parts.

Figure Number	Figure Caption
Figure 15-4	Logic Supply Current, I_{CC} vs. T_C (INx = 0 V)
Figure 15-5	Logic Supply Current, I_{CC} vs. T_C (INx = 5 V)
Figure 15-6	VCCx Pin Voltage, V _{CC} vs. Logic Supply Current, I _{CC}
Figure 15-7	Logic Supply Current (1-phase) I_{BS} vs. T_C (HINx = 0 V)
Figure 15-8	Logic Supply Current (1-phase) I_{BS} vs. T_C (HINx = 5 V)
Figure 15-9	VBx Pin Voltage, V_B vs. Logic Supply Current, I_{BS} (HINx = 0 V)
Figure 15-10	Logic Operation Start Voltage, V _{BS(ON)} vs. T _C
Figure 15-11	Logic Operation Stop Voltage, V _{BS(OFF)} vs. T _C
Figure 15-12	Logic Operation Start Voltage, V _{CC(ON)} vs. T _C
Figure 15-13	Logic Operation Stop Voltage, V _{CC(OFF)} vs. T _C
Figure 15-14	UVLO_VB Filtering Time vs. T _C
Figure 15-15	UVLO_VCC Filtering Time vs. T _C
Figure 15-16	High Level Input Threshold Voltage, V_{IH} vs. T_C
Figure 15-17	Low Level Input Threshold Voltage, V _{IL} vs. T _C
Figure 15-18	Input Current at High Level (HINx or LINx), IIN vs. T _C
Figure 15-19	High-side Turn-on Propagation Delay vs. T _C (from HINx to HOx)
Figure 15-20	Low-side Turn-on Propagation Delay vs. T _C (from LINx to LOx)
Figure 15-21	Minimum Transmittable Pulse Width for High-side Switching, t _{HIN(MIN)} vs. T _C
Figure 15-22	Minimum Transmittable Pulse Width for Low-side Switching, t _{LIN(MIN)} vs. T _C
Figure 15-23	SD Pin Filtering Time vs. T _C
Figure 15-24	FO Pin Filtering Time vs. T _C
Figure 15-25	Current Limit Reference Voltage, V _{LIM} vs. T _C
Figure 15-26	OCP Threshold Voltage, V _{TRIP} vs. T _C
Figure 15-27	OCP Hold Time, t _P ys. T _C
Figure 15-28	OCP Blanking Time, t _{BK(OCP)} vs. T _C ; Current Limit Blanking Time, t _{BK(OCL)} vs. T _C

Table 15-1. Typical Characteristics of Control Parts





Figure 15-5. Logic Supply Current, I_{CC} vs. T_C (INx = 5 V)



180

160 140

120

100

80

60

40

12

13

14





VBx = 15 V, HINx = 0 V

−3Ò °C

18

17

125 °C

20

25 °C

19







Figure 15-10. Logic Operation Start Voltage, $V_{BS(ON)}$ vs. T_C

Figure 15-9. VBx Pin Voltage, V_B vs. Logic Supply Current, I_{BS} (HINx = 0 V)

15

16

 $V_{B}(V)$



Figure 15-11. Logic Operation Stop Voltage, $V_{BS(OFF)}$ vs. T_C













Figure 15-16. High Level Input Threshold Voltage, $$V_{IH}\,vs.\,T_C$$

Figure 15-15. UVLO_VCC Filtering Time vs. T_C



Figure 15-17. Low Level Input Threshold Voltage, V_{IL} vs. T_{C}

Low-side Turn-on Propagation



Figure 15-18. Input Current at High Level (HINx or LINx), $I_{\rm IN}$ vs. $T_{\rm C}$





Figure 15-20. Low-side Turn-on Propagation Delay vs. T_C (from LINx to LOx)



Figure 15-22. Minimum Transmittable Pulse Width for Low-side Switching, $t_{LIN(MIN)}$ vs. T_C

Figure 15-21. Minimum Transmittable Pulse Width for High-side Switching, t_{HIN(MIN)} vs. T_C



Figure 15-23. SD Pin Filtering Time vs. $T_{\rm C}$













Figure 15-27. OCP Hold Time, t_P vs. T_C

15.3 Performance Curves of Output Parts

15.3.1 Output Transistor Performance Curves

15.3.1.1. SIM6811M



Figure 15-29. Power MOSFET RDS(ON) vs. ID



15.3.1.2. SIM6812M


15.3.1.3. SIM6880M



15.3.1.4. SIM6822MV



Figure 15-35. IGBT V_{CE(SAT)} vs. I_C



15.3.2 Switching Loss Curves

Conditions: VBB pin voltage = 300 V, half-bridge circuit with inductive load. Switching Loss, E, is the sum of turn-on loss and turn-off loss.

15.3.2.1. SIM6811M





15.3.2.2. SIM6812M



Figure 15-40. Low-side Switching Loss

15.3.2.3. SIM6880M



Figure 15-41. High-side Switching Loss



15.3.2.4. SIM6822MV



Figure 15-43. High-side Switching Loss

Figure 15-44. Low-side Switching Loss

15.4 Allowable Effective Current Curves

The following curves represent allowable effective currents in 3-phase sine-wave PWM driving with parameters such as typical $R_{DS(ON)}$ or $V_{CE(SAT)}$, and typical switching losses.

Operating conditions: VBB pin input voltage, $V_{DC} = 300$ V; VCC pin input voltage, $V_{CC} = 15$ V; modulation index, M = 0.9; motor power factor, $\cos\theta = 0.8$; junction temperature, $T_J = 150$ °C.

15.4.1 SIM6811M







Figure 15-46. Allowable Effective Current ($f_c = 16 \text{ kHz}$): SIM6811M

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15.4.2 SIM6812M







Figure 15-48. Allowable Effective Current ($f_C = 16 \text{ kHz}$): SIM6812M

15.4.3 SIM6880M



Figure 15-50. Allowable Effective Current ($f_C = 16 \text{ kHz}$): SIM6880M

15.4.4 SIM6822MV



Figure 15-51. Allowable Effective Current ($f_c = 2 \text{ kHz}$): SIM6822MV



Figure 15-52. Allowable Effective Current ($f_C = 16 \text{ kHz}$): SIM6822MV

15.5 Short Circuit SOAs (Safe Operating Areas)

This section provides the graphs illustrating the short circuit SOAs of the SIM6800M/MV series devices whose output transistors consist of built-in IGBTs.

Conditions: $V_{DC} \le 400$ V, 13.5 V \le VCC ≤ 16.5 V, $T_J = 125$ °C, 1 pulse.



Figure 15-54. Short Circuit SOA: SIM6822MV

16. Pattern Layout Example

This section contains the schematic diagrams of a PCB pattern layout example using an SIM6800M/MV series device. For more details on through holes, see Section 10.



Figure 16-2. Bottom View



17. Typical Motor Driver Application

This section contains the information on the typical motor driver application listed in the previous section, including a circuit diagram, specifications, and the bill of the materials used.

• Motor Driver Specifications

IC	SIM6822MV
Main Supply Voltage, V _{DC}	300 VDC (typ.)
Rated Output Power	500 W

• Circuit Diagram

See Figure 16-3.

• Bill of Materials

Part Type lectrolytic	Ratings	Symbol	Part Type	
lectrolytic		bymoor	Fait Type	Ratings
lectionytic	47 μF, 50 V	R3	General	100 Ω, 1/8 W
lectrolytic	47 μF, 50 V	R4	General	100 Ω, 1/8 W
lectrolytic	47 μF, 50 V	R5	General	100 Ω, 1/8 W
lectrolytic	100 μF, 50 V	R6	General	100 Ω, 1/8 W
eramic	0.1 µF, 50 V	R7*	Metal plate	0.15 Ω, 2 W
eramic	0.1 µF, 50 V	R8*	Metal plate	0.15 Ω, 2 W
eramic	0.1 µF, 50 V	R9*	Metal plate	0.15 Ω, 2 W
eramic	0.1 μF, 50 V	R10	General	100 Ω, 1/8 W
eramic	0.1 µF, 50 V	R16	General	3.3 kΩ, 1/8 W
eramic	100 pF, 50 V	R17	General	0 kΩ, 1/8 W
eramic	100 pF, 50 V	R18	General	100 Ω, 1/8 W
eramic	100 pF, 50 V	R19	General	100 Ω, 1/8 W
eramic	100 pF, 50 V	R20	General	100 Ω, 1/8 W
eramic	100 pF, 50 V	R21	General	Open
eramic	100 pF, 50 V	R22	General	Open
eramic	100 pF, 50 V	R23	General	Open
eramic	100 pF, 50 V	ZD1	Zener diode	$V_{Z} = 21 V (max.)$
eramic	100 pF, 50 V	IPM1	IC	SIM6822MV
eramic	0.01 µF, 50 V	CN1	Pin header	Equiv. to B2P3-VH
eramic	100 pF, 50 V	CN2	Pin header	Equiv. to B2P5-VH
ilm	0.033 μF, 630 V	CN3	Connector	Equiv. to MA06-1
eneral	100 Ω, 1/8 W	CN4	Connector	Equiv. to MA10-1
eneral	100 Ω, 1/8 W			
	ectrolytic ectrolytic ectrolytic eramic	ectrolytic 47 μF, 50 V ectrolytic 47 μF, 50 V ectrolytic 100 μF, 50 V ectrolytic 100 μF, 50 V eramic 0.1 μF, 50 V eramic 100 pF, 50 V	ectrolytic47 μF, 50 VR4ectrolytic47 μF, 50 VR5ectrolytic100 μF, 50 VR6eramic0.1 μF, 50 VR7*eramic0.1 μF, 50 VR8*eramic0.1 μF, 50 VR9*eramic0.1 μF, 50 VR10eramic0.1 μF, 50 VR16eramic0.1 μF, 50 VR17eramic100 pF, 50 VR17eramic100 pF, 50 VR17eramic100 pF, 50 VR19eramic100 pF, 50 VR20eramic100 pF, 50 VR21eramic100 pF, 50 VR23eramic100 pF, 50 VR23eramic100 pF, 50 VCN1eramic100 pF, 50 VCN2lm0.033 μF, 630 VCN3eneral100 Ω, 1/8 WCN4	ectrolytic47 μ F, 50 VR4Generalectrolytic47 μ F, 50 VR5Generalectrolytic100 μ F, 50 VR6Generaleramic0.1 μ F, 50 VR7*Metal plateeramic0.1 μ F, 50 VR9*Metal plateeramic0.1 μ F, 50 VR9*Metal plateeramic0.1 μ F, 50 VR9*Metal plateeramic0.1 μ F, 50 VR10Generaleramic0.1 μ F, 50 VR16Generaleramic0.1 μ F, 50 VR16Generaleramic100 pF, 50 VR17Generaleramic100 pF, 50 VR17Generaleramic100 pF, 50 VR19Generaleramic100 pF, 50 VR20Generaleramic100 pF, 50 VR21Generaleramic100 pF, 50 VR23Generaleramic100 pF, 50 VZD1Zener diodeeramic100 pF, 50 VIPM1ICeramic100 pF, 50 VCN1Pin headereramic100 pF, 50 VCN1Pin headereramic100 pF, 50 VCN1Pin headereramic100 pF, 50 VCN1Pin header

* Refers to a part that requires adjustment based on operation performance in an actual application.

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